Form PTO-1449
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INFORMATION DISCOSURE TATION
IN AN APPLICATION

(Use several sheets if necessary)

	Sheet 1 01 2
Docket Number 416272004201	Application Number 10/729,726
Applicant	
Sung-Mo KAN	NG and Seung-Moon YOO
Filing Date December 5, 2003	Group Art Unit 2838 28/6
Mailing Date April 5, 2004	

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**EXAMINER:** 

Jeffrey Zweizig

DATE CONSIDERED:

11/22/04

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

sf-1661650 PTO/SB/ 08 (2-92)

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Form PTO-1449			Docket Number 416272004201	Application Number 10/729,726			
INFORMATION DISCLOSURE CITATION			Applicant				
	IN.	AN APPLICATION	Sung-Mo KANG and Seung-Moon YOO				
	(Us	e several sheets if necessary)	Filing Date December 5, 2003	Group Art Unit 2838			
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EXAMINER: Jeffrey Zweizig DATE CONSIDERED: 1/22/04							

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ALTERNATIVE TO PTO/SB/06a/b (08-03)

Substitute for form 1449/PTO			4	Complete If Known		
	<b></b>			Application Number	10/729,726	
			SCLOSURE	Filing Date	December 5, 2003	
S	STATEMENT BY APPLICANT			First Named Inventor	Sung-Mo KANG	
	Also so many			Art Unit	2816	
	(Use as many sheets as necessary)			Examiner Name	J. S. Zweizig	
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		NON PATENT LITERATURE DOCUMENTS	_
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Examiner	Jothron TWOIZIA	Date	11 (1)
Signature	JETTIEY LWEIZIG	Considered	11/22/04
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<sup>&</sup>lt;sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.